

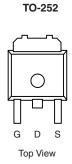
## AM14N25-280D-VB Datasheet N-Channel 250 V (D-S) 175 °C MOSFET

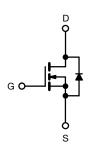
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	250			
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V	0.176		
Q <sub>g</sub> max. (nC)	68			
Q <sub>gs</sub> (nC)	11			
Q <sub>gd</sub> (nC)	35			
Configuration	Single			

#### **FEATURES**

- Dynamic dV/dt rating
- Repetitive avalanche rated
- · Fast switching
- Ease of paralleling
- Simple drive requirements







N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	250	.,	
Gate-Source Voltage			V <sub>GS</sub>	± 20	V	
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25  ^{\circ}{\rm C}$ $T_{\rm C} = 100  ^{\circ}{\rm C}$		17		
		T <sub>C</sub> = 100 °C	I <sub>D</sub>	11	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	56		
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	550	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	17	А	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	13	mJ	
Maximum Power Dissipation	T <sub>C</sub> =	25 °C	P <sub>D</sub>	125	W	
Peak Diode Recovery dV/dt c			dV/dt	4.8	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	00	
Soldering Recommendations (Peak temperature) d	for 10 s			300	°C	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
				1.1	N·m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD}=50$  V, starting  $T_J=25$  °C, L=4.5 mH,  $R_g=25$   $\Omega$ ,  $I_{AS}=14$  A (see fig. 12). c.  $I_{SD}\leq 14$  A,  $dI/dt\leq 150$  A/µs,  $V_{DD}\leq V_{DS},$   $T_J\leq 150$  °C. d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	=	62		
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	1.0		

PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static					Į.	Į.	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		250	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.34	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
Zero Gate Voltage Drain Current	1	V <sub>DS</sub> = 250 V, V <sub>GS</sub> = 0 V	-	-	25	μA	
Zero Gate Voltage Drain Gurrent	I <sub>DSS</sub>	$V_{DS} = 200 \text{ V}$	, $V_{GS}$ = 0 V, $T_J$ = 125 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 8.4 A <sup>b</sup>	-	0.176	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 8.4 A <sup>b</sup>		6.7	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. } 5$		-	1300	-	pF
Output Capacitance	C <sub>oss</sub>			-	330	-	
Reverse Transfer Capacitance	$C_{rss}$			=.	85	-	
Total Gate Charge	Qg	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 7.9 A, V <sub>DS</sub> = 200 V, see fig. 6 and 13 <sup>b</sup>	=	-	68	nC
Gate-Source Charge	Q <sub>gs</sub>			-	-	11	
Gate-Drain Charge	Q <sub>gd</sub>			-	-	35	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD}$ = 125 V, $I_{D}$ = 7.9 A, $R_{g}$ = 9.1 $\Omega$ , $R_{D}$ = 8.7 $\Omega$ , see fig. 10 <sup>b</sup>		-	11	-	- ns
Rise Time	t <sub>r</sub>			-	24	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	53	-	
Fall Time	t <sub>f</sub>			=	49	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	- nH
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	
Gate Input Resistance	$R_g$	f = 1 MHz, open drain		0.3	-	1.2	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	14	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	56	A
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 14 A, V <sub>GS</sub> = 0 V b		-	-	1.8	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = 7.9 \text{ A, dI/dt} = 100 \text{ A/}\mu\text{s}^{\text{b}}$		-	250	500	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	2.3	4.6	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated			minated b	v Le and	L <sub>D</sub> )

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq 300~\mu s;$  duty cycle  $\leq 2~\%.$



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

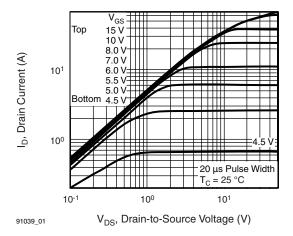


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

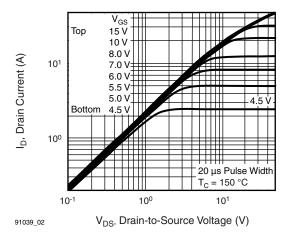


Fig. 2 - Typical Output Characteristics,  $T_C = 150 \, ^{\circ}\text{C}$ 

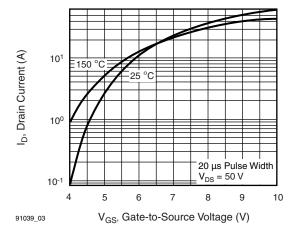


Fig. 3 - Typical Transfer Characteristics

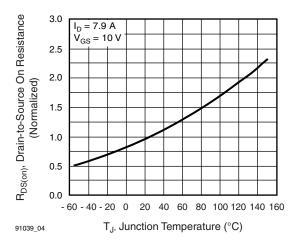


Fig. 4 - Normalized On-Resistance vs. Temperature

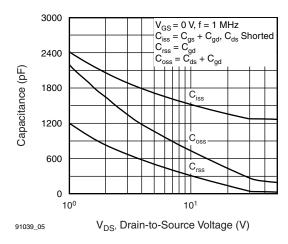


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

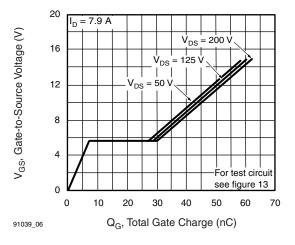


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



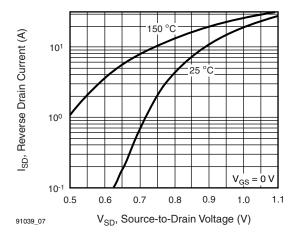


Fig. 7 - Typical Source-Drain Diode Forward Voltage

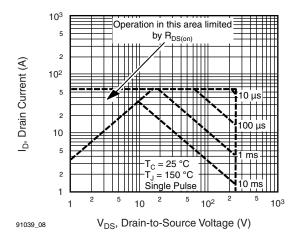


Fig. 8 - Maximum Safe Operating Area

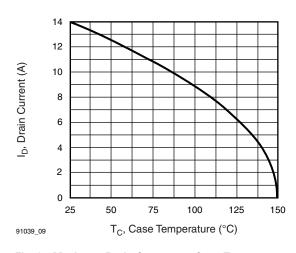


Fig. 9 - Maximum Drain Current vs. Case Temperature

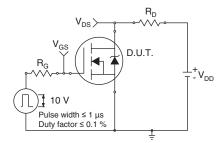


Fig. 10a - Switching Time Test Circuit

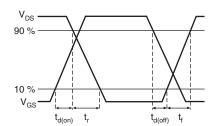


Fig. 10b - Switching Time Waveforms

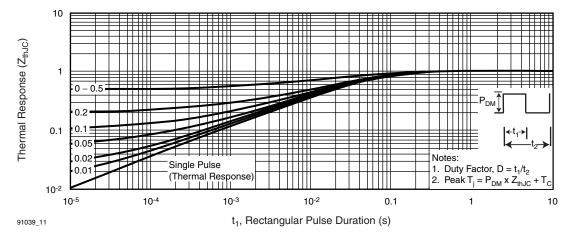
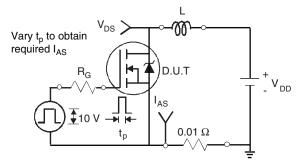


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

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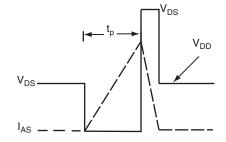


Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

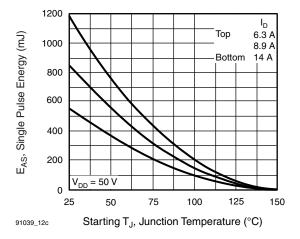


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

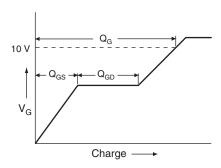


Fig. 13a - Basic Gate Charge Waveform

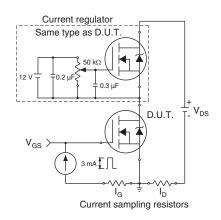
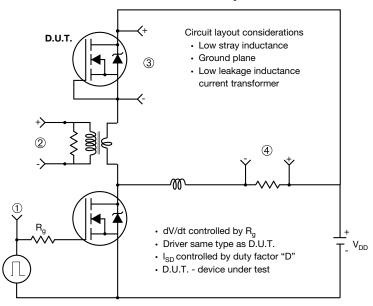


Fig. 13b - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



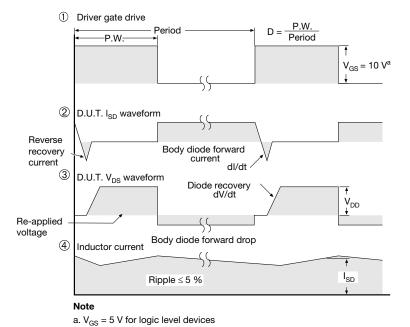


Fig. 14 - For N-Channel



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